



YOUSHANG SEMICONDUCTOR

**设计研发新型功率器件**

**各类小信号开关**

**中低压及高压大电流等场效应管**

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企业QQ二维码

## Product Summary

Device	$V_{(BR)DSS}$	$R_{DS(on)}$ max	$I_D$ Max $T_A = +25^\circ\text{C}$
Q1	20V	$20\text{m}\Omega @ V_{GS} = 4.5\text{V}$	8.5A
		$28\text{m}\Omega @ V_{GS} = 2.5\text{V}$	7.2A
Q2	-20V	$33\text{m}\Omega @ V_{GS} = -4.5\text{V}$	-6.8A
		$45\text{m}\Omega @ V_{GS} = -2.5\text{V}$	-5.8A

## Description and Applications

This MOSFET has been designed to minimize the on-state resistance ( $R_{DS(ON)}$ ) and yet maintain superior switching performance, making it ideal for high efficiency power management applications.

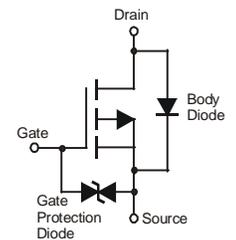
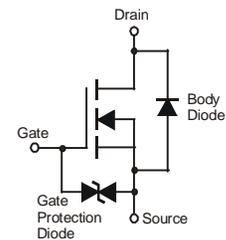
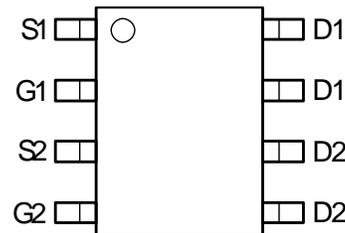
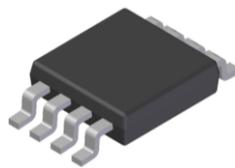
- Motor control
- DC-DC Converters
- Power management functions
- Notebook Computers and Printers

## Features and Benefits

- Reduced footprint with two discretes in a single SO8
- Low gate drive
- Low input capacitance
- Fast Switching Speed
- Low Input/Output Leakage

## Mechanical Data

- Case: SO-8
- Case Material: Molded Plastic, "Green" Molding Compound. UL Flammability Classification Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020
- Terminals Connections: See Diagram
- Terminals: Finish - Matte Tin annealed over Copper lead frame. Solderable per MIL-STD-202, Method 208 
- Weight: 0.074 grams (approximate)



**Maximum Ratings** (@ $T_A = +25^\circ\text{C}$ , unless otherwise specified.)

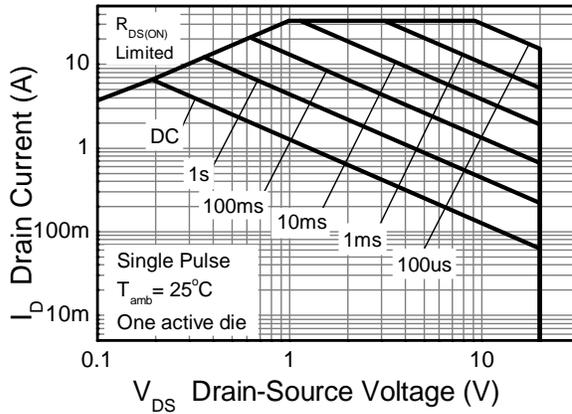
Characteristic			Symbol	N-Channel - Q1	P-Channel - Q2	Units
Drain-Source Voltage			$V_{DSS}$	20	-20	V
Gate-Source Voltage			$V_{GSS}$	$\pm 10$	$\pm 10$	
Continuous Drain Current	$V_{GS} = 4.5\text{V}$	(Notes 6 & 8)	$I_D$	8.5	-6.8	A
		$T_A = 70^\circ\text{C}$ (Notes 6 & 8)		6.8	-5.4	
		(Notes 5 & 8)		6.5	-5.2	
		(Notes 5 & 9)		7.8	-6.3	
Pulsed Drain Current	$V_{GS} = 4.5\text{V}$	(Notes 7 & 8)	$I_{DM}$	33.6	-26.8	
Continuous Source Current (Body diode)			$I_S$	4.0	-4.0	
Pulsed Source Current (Body diode)			$I_{SM}$	33.6	-26.8	

**Thermal Characteristics** (@ $T_A = +25^\circ\text{C}$ , unless otherwise specified.)

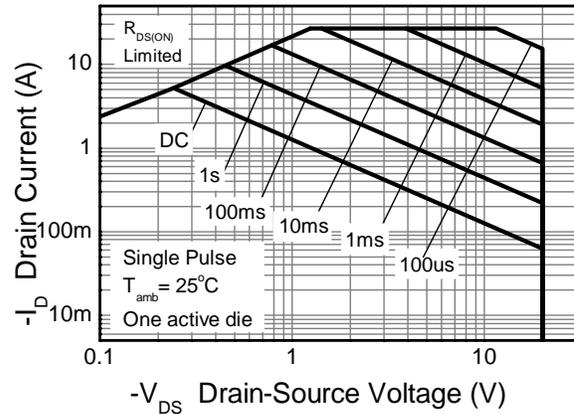
Characteristic		Symbol	N-Channel - Q1	P-Channel - Q2	Unit
Power Dissipation Linear Derating Factor	(Notes 5 & 8)	$P_D$	1.25		W mW/ $^\circ\text{C}$
			10		
	(Notes 5 & 9)		1.8		
	(Notes 6 & 8)		14.3		
Thermal Resistance, Junction to Ambient	(Notes 5 & 8)	$R_{\theta JA}$	100		$^\circ\text{C/W}$
	(Notes 5 & 9)		70		
	(Notes 6 & 8)		58		
Thermal Resistance, Junction to Lead	(Notes 8 & 10)	$R_{\theta JL}$	51		
Operating and Storage Temperature Range			$T_J, T_{STG}$	-55 to +150	$^\circ\text{C}$

- Notes:
5. For a device surface mounted on 25mm x 25mm x 1.6mm FR4 PCB with high coverage of single sided 1oz copper, in still air conditions; the device is measured when operating in a steady-state condition.
  6. Same as note (2), except the device is measured at  $t \leq 10$  sec.
  7. Same as note (2), except the device is pulsed with  $D = 0.02$  and pulse width 300 $\mu\text{s}$ .
  8. For a dual device with one active die.
  9. For a device with two active die running at equal power.
  10. Thermal resistance from junction to solder-point (at the end of the drain lead).

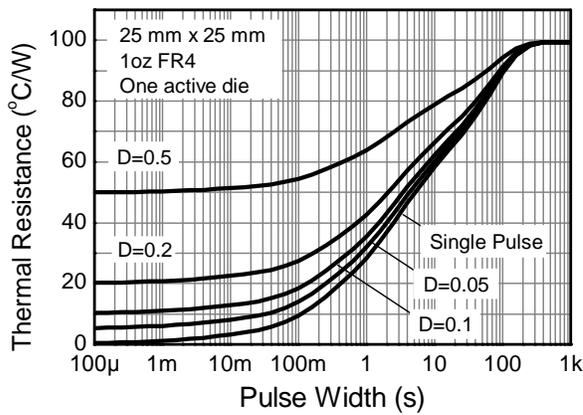
**Thermal Characteristics**



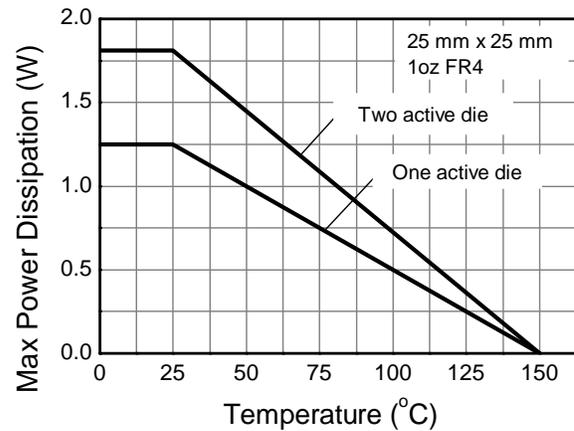
**N-channel Safe Operating Area**



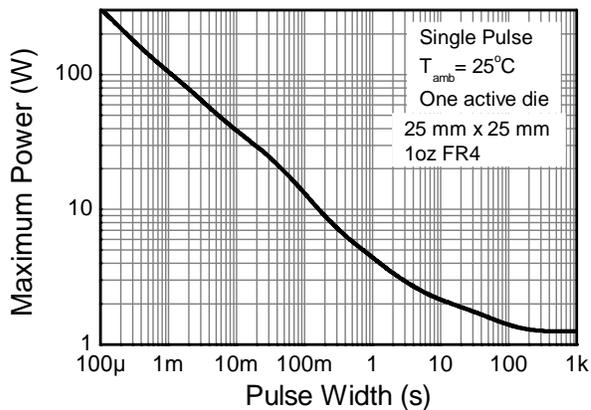
**P-channel Safe Operating Area**



**Transient Thermal Impedance**



**Derating Curve**



**Pulse Power Dissipation**

**Electrical Characteristics – Q1 N-CHANNEL** (@T<sub>A</sub> = +25°C, unless otherwise specified.)

Characteristic	Symbol	Min	Typ	Max	Unit	Test Condition
<b>OFF CHARACTERISTICS</b>						
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	20	—	—	V	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	—	—	1.0	μA	V <sub>DS</sub> = 20V, V <sub>GS</sub> = 0V
Gate-Source Leakage	I <sub>GSS</sub>	—	—	±10	μA	V <sub>GS</sub> = ±10V, V <sub>DS</sub> = 0V
<b>ON CHARACTERISTICS</b>						
Gate Threshold Voltage	V <sub>GS(th)</sub>	0.5	1.1	1.5	V	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250μA
Static Drain-Source On-Resistance (Note 11)	R <sub>DS(on)</sub>	—	13	20	mΩ	V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 7A
			18	28		V <sub>GS</sub> = 2.5V, I <sub>D</sub> = 3A
Forward Transfer Admittance (Notes 11 & 12)	Y <sub>fs</sub>	—	16	—	S	V <sub>DS</sub> = 5V, I <sub>D</sub> = 9.4A
Diode Forward Voltage (Note 11)	V <sub>SD</sub>	—	0.7	1.2	V	V <sub>GS</sub> = 0V, I <sub>S</sub> = 1.3A
Continuous Source Current	I <sub>S</sub>	—	—	1.8	A	—
<b>DYNAMIC CHARACTERISTICS (Note 12)</b>						
Input Capacitance	C <sub>iss</sub>	—	1149	—	pF	V <sub>DS</sub> = 10V, V <sub>GS</sub> = 0V, f = 1.0MHz
Output Capacitance	C <sub>oss</sub>	—	157	—		
Reverse Transfer Capacitance	C <sub>rss</sub>	—	142	—		
Gate Resistance	R <sub>g</sub>	—	1.51	—	Ω	V <sub>DS</sub> = 0V, V <sub>GS</sub> = 0V, f = 1MHz
Total Gate Charge (Note 13)	Q <sub>g</sub>	—	6.0	—	nC	V <sub>GS</sub> = 2.5V  V <sub>GS</sub> = 4.5V  V <sub>DS</sub> = 10V I <sub>D</sub> = 9.4A
Total Gate Charge (Note 13)	Q <sub>g</sub>	—	11.6	—		
Gate-Source Charge (Note 13)	Q <sub>gs</sub>	—	2.7	—		
Gate-Drain Charge (Note 13)	Q <sub>gd</sub>	—	3.4	—		
Turn-On Delay Time (Note 13)	t <sub>D(on)</sub>	—	11.67	—		
Turn-On Rise Time (Note 13)	t <sub>r</sub>	—	12.49	—	ns	V <sub>GS</sub> = 4.5V, V <sub>DS</sub> = 10V, R <sub>G</sub> = 6Ω, I <sub>D</sub> = 1A
Turn-Off Delay Time (Note 13)	t <sub>D(off)</sub>	—	35.89	—		
Turn-Off Fall Time (Note 13)	t <sub>f</sub>	—	12.33	—		

Notes: 11. Measured under pulsed conditions. Pulse width ≤ 300μs; duty cycle ≤ 2%  
 12. For design aid only, not subject to production testing.  
 13. Switching characteristics are independent of operating junction temperatures.

**Typical Characteristics – Q1 N-CHANNEL**

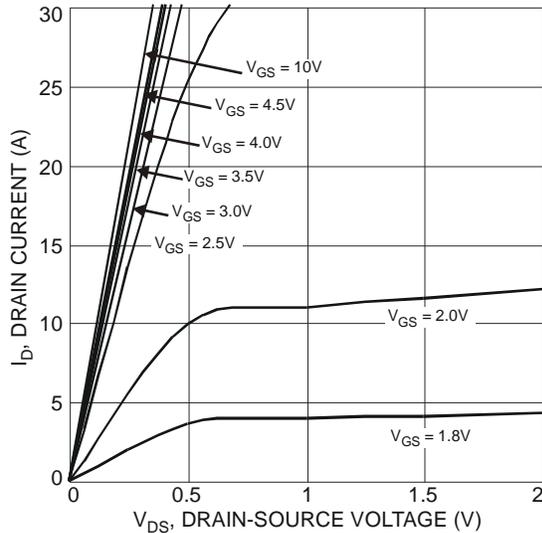


Fig. 1 Typical Output Characteristics

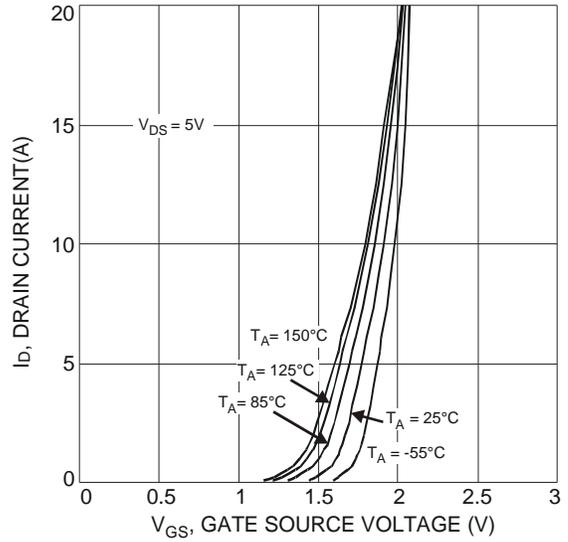


Fig. 2 Typical Transfer Characteristics

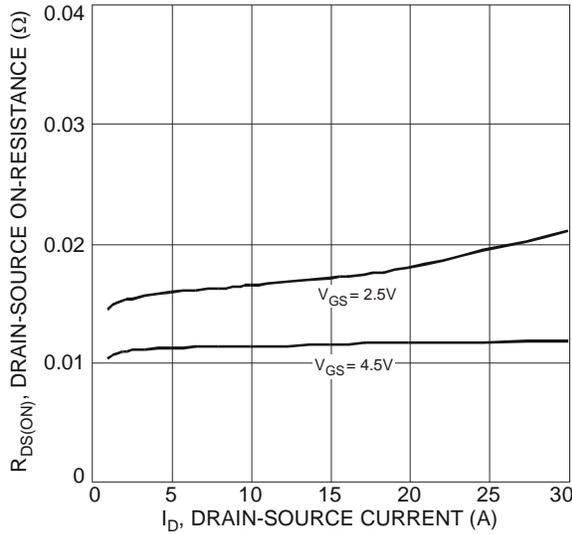


Fig. 3 Typical On-Resistance vs. Drain Current and Gate Voltage

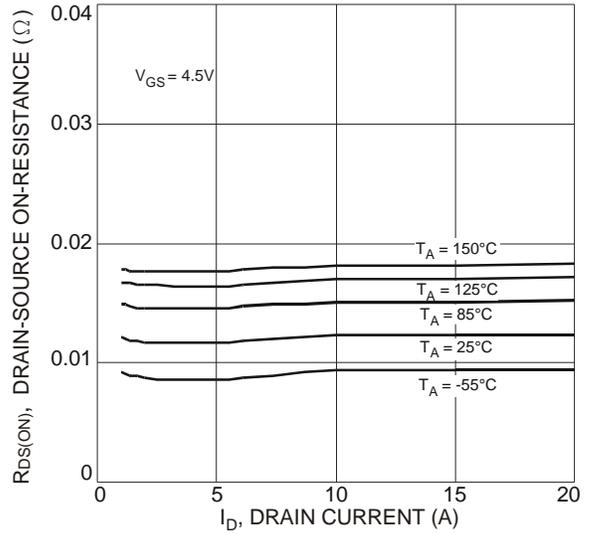


Fig. 4 Typical Drain-Source On-Resistance vs. Drain Current and Temperature

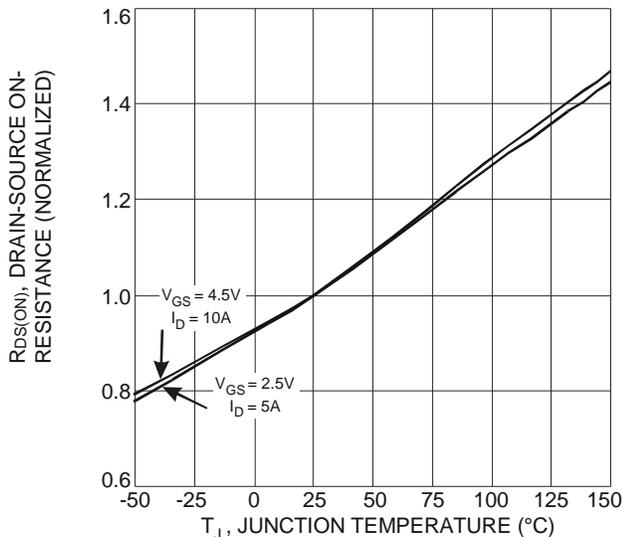


Fig. 5 On-Resistance Variation with Temperature

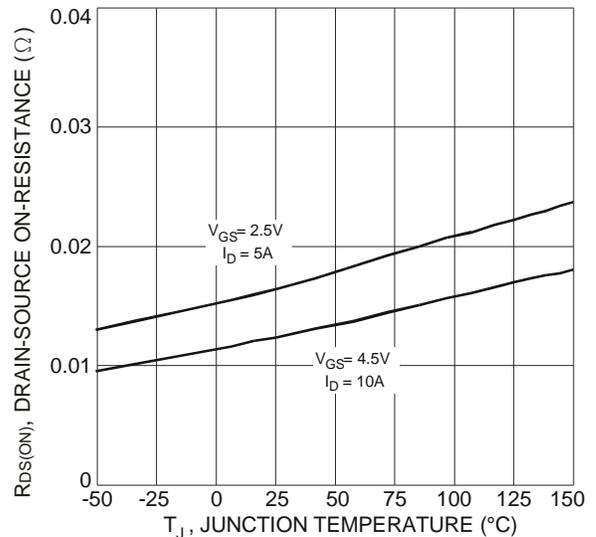


Fig. 6 On-Resistance Variation with Temperature

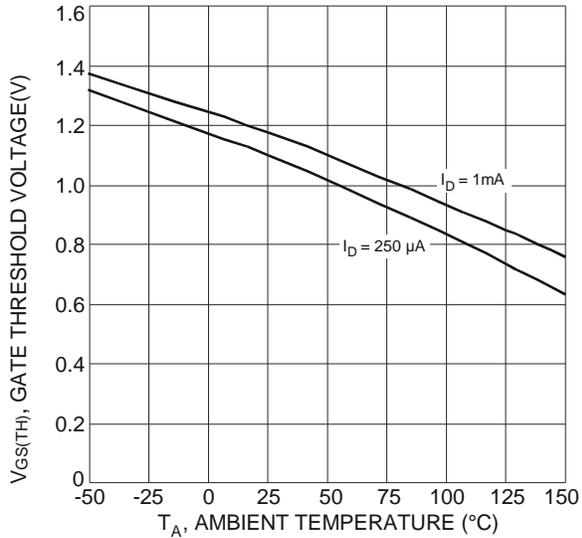


Fig. 7 Gate Threshold Variation vs. Ambient Temperature

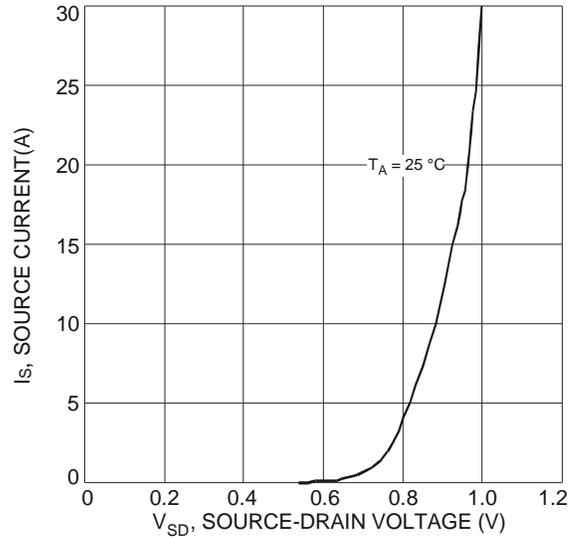


Fig. 8 Diode Forward Voltage vs. Current

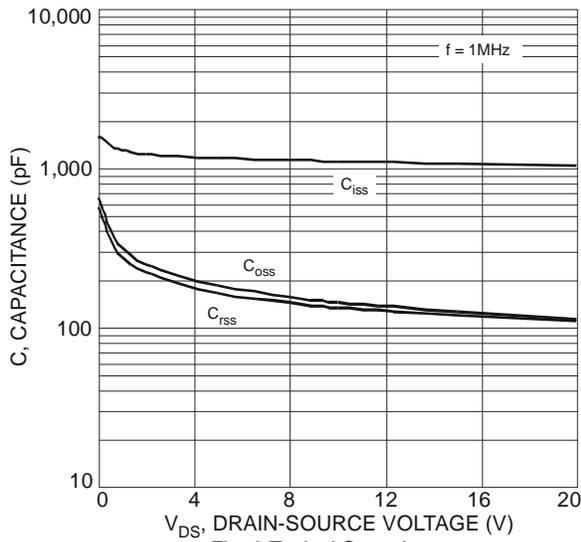


Fig. 9 Typical Capacitance

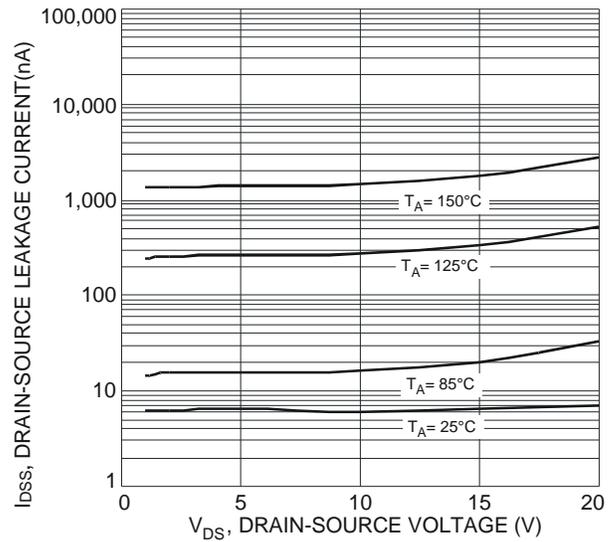


Fig. 10 Typical Drain-Source Leakage Current vs. Drain-Source Voltage

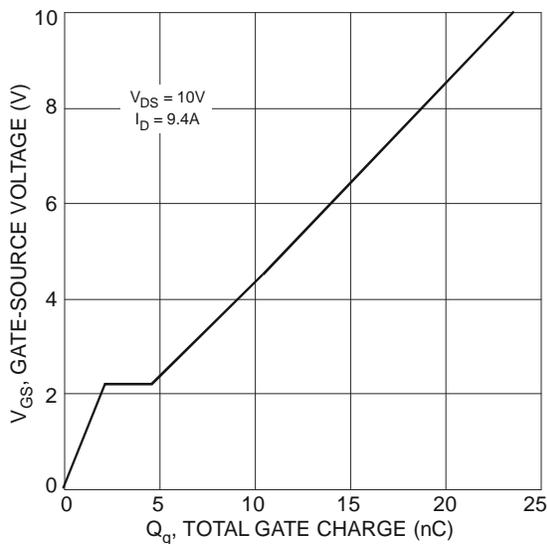


Fig. 11 Gate-Source Voltage vs. Total Gate Charge

**Electrical Characteristics – Q2 P-CHANNEL** (@T<sub>A</sub> = +25°C, unless otherwise specified.)

Characteristic	Symbol	Min	Typ	Max	Unit	Test Condition
<b>OFF CHARACTERISTICS</b>						
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	-20	—	—	V	V <sub>GS</sub> = 0V, I <sub>D</sub> = -250μA
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	—	—	-1.0	μA	V <sub>DS</sub> = -20V, V <sub>GS</sub> = 0V
Gate-Source Leakage	I <sub>GSS</sub>	—	—	±10	μA	V <sub>GS</sub> = ±8V, V <sub>DS</sub> = 0V
<b>ON CHARACTERISTICS (Note 10)</b>						
Gate Threshold Voltage	V <sub>GS(th)</sub>	-0.4	-0.7	-1.0	V	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = -250μA
Static Drain-Source On-Resistance (Note 14)	R <sub>DS(on)</sub>	—	26	33	mΩ	V <sub>GS</sub> = -4.5V, I <sub>D</sub> = -6A
			33	45		V <sub>GS</sub> = -2.5V, I <sub>D</sub> = -3A
Forward Transfer Admittance (Note 14 & 15)	Y <sub>fs</sub>	—	14	—	S	V <sub>DS</sub> = -5V, I <sub>D</sub> = -4A
Diode Forward Voltage (Note 14)	V <sub>SD</sub>	—	-0.7	-1.0	V	V <sub>GS</sub> = 0V, I <sub>S</sub> = -1A
Continuous Source Current	I <sub>S</sub>	—	—	-1.8	A	-
<b>DYNAMIC CHARACTERISTICS (Note 15)</b>						
Input Capacitance	C <sub>iss</sub>	—	1610	—	pF	V <sub>DS</sub> = -10V, V <sub>GS</sub> = 0V, f = 1.0MHz
Output Capacitance	C <sub>oss</sub>	—	157	—		
Reverse Transfer Capacitance	C <sub>rss</sub>	—	145	—		
Gate Resistance	R <sub>g</sub>	—	9.45	—	Ω	V <sub>DS</sub> = 0V, V <sub>GS</sub> = 0V, f = 1MHz
Total Gate Charge (Note 16)	Q <sub>g</sub>	—	8.0	—	nC	V <sub>GS</sub> = -2.5V V <sub>GS</sub> = -4.5V V <sub>DS</sub> = -10V I <sub>D</sub> = -4A
Total Gate Charge (Note 16)	Q <sub>g</sub>	—	15.4	—		
Gate-Source Charge (Note 16)	Q <sub>gs</sub>	—	2.5	—		
Gate-Drain Charge (Note 16)	Q <sub>gd</sub>	—	3.3	—		
Turn-On Delay Time (Note 16)	t <sub>D(on)</sub>	—	16.8	—	ns	V <sub>GS</sub> = -4.5V, V <sub>DS</sub> = -10V, R <sub>G</sub> = 6Ω, I <sub>D</sub> = -1A
Turn-On Rise Time (Note 16)	t <sub>r</sub>	—	12.4	—		
Turn-Off Delay Time (Note 16)	t <sub>D(off)</sub>	—	94.1	—		
Turn-Off Fall Time (Note 16)	t <sub>f</sub>	—	42.4	—		

Notes: 14. Measured under pulsed conditions. Pulse width ≤ 300μs; duty cycle ≤ 2%  
 15. For design aid only, not subject to production testing.  
 16. Switching characteristics are independent of operating junction temperatures.

**Typical Characteristics – Q2 P-CHANNEL**

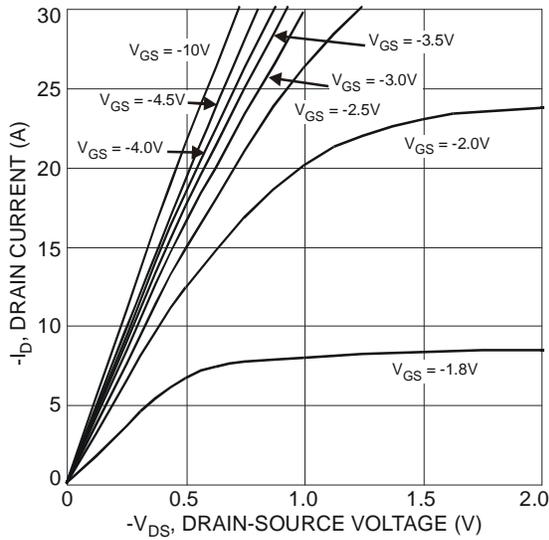


Fig. 12 Typical Output Characteristics

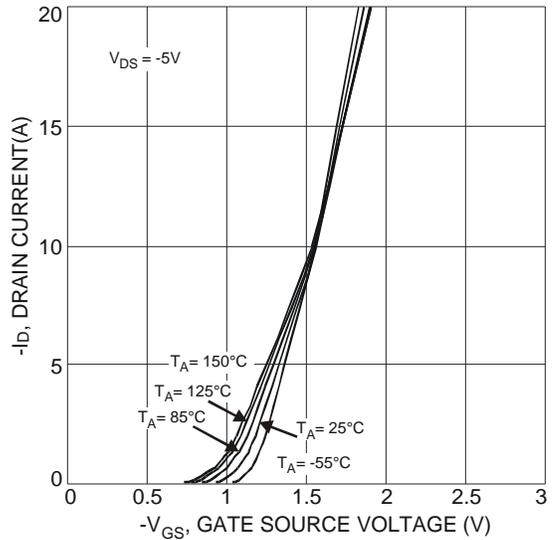


Fig. 13 Typical Transfer Characteristics

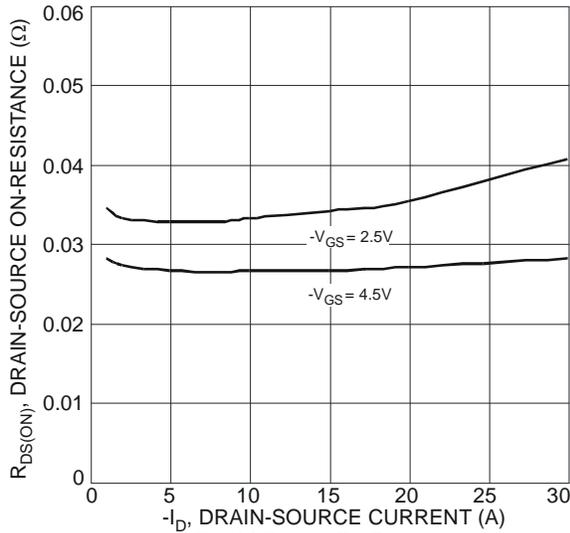


Fig. 14 Typical On-Resistance vs. Drain Current and Gate Voltage

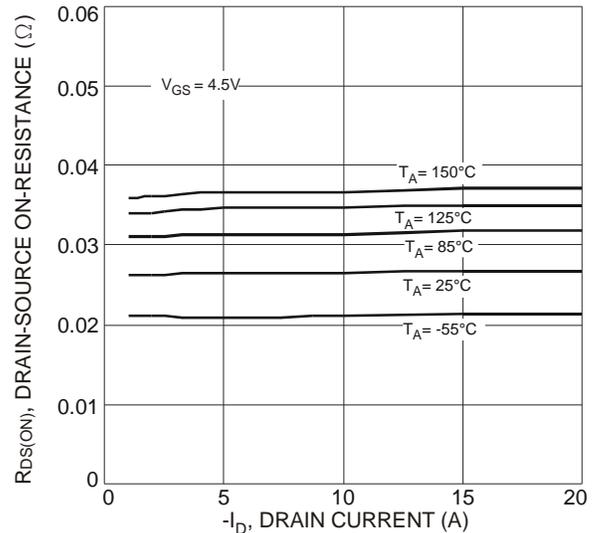


Fig. 15 Typical Drain-Source On-Resistance vs. Drain Current and Temperature

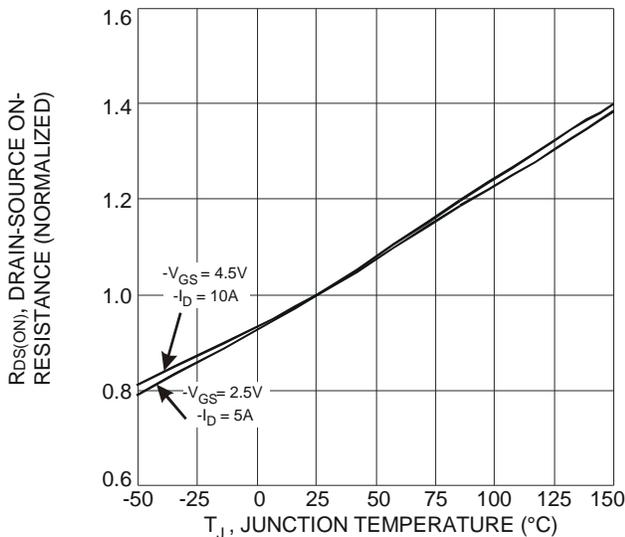


Fig. 16 On-Resistance Variation with Temperature

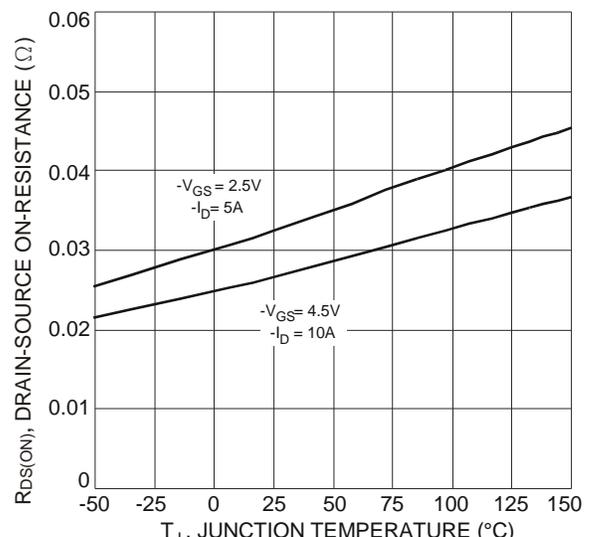


Fig. 17 On-Resistance Variation with Temperature

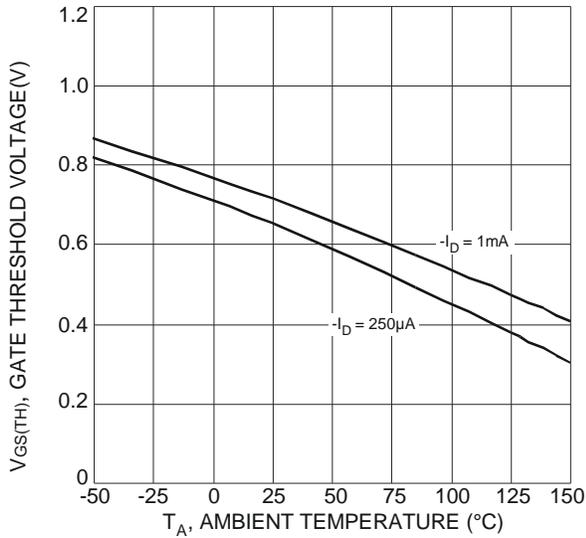


Fig. 18 Gate Threshold Variation vs. Ambient Temperature

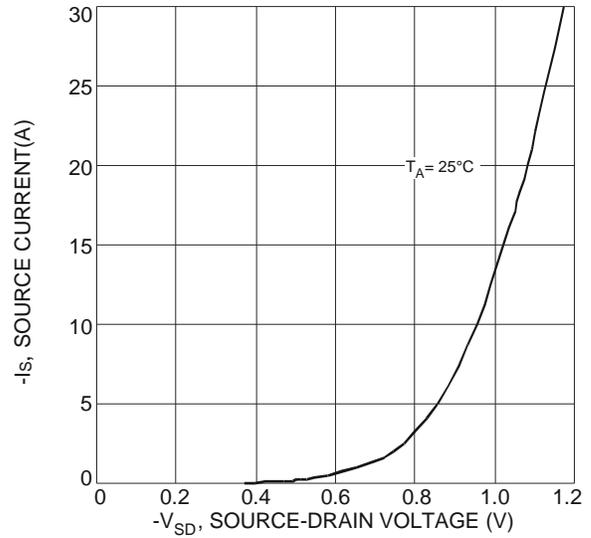


Fig. 19 Diode Forward Voltage vs. Current

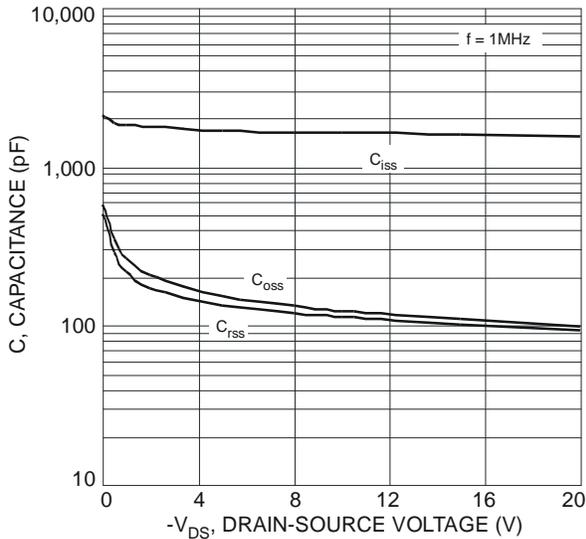


Fig. 20 Typical Capacitance

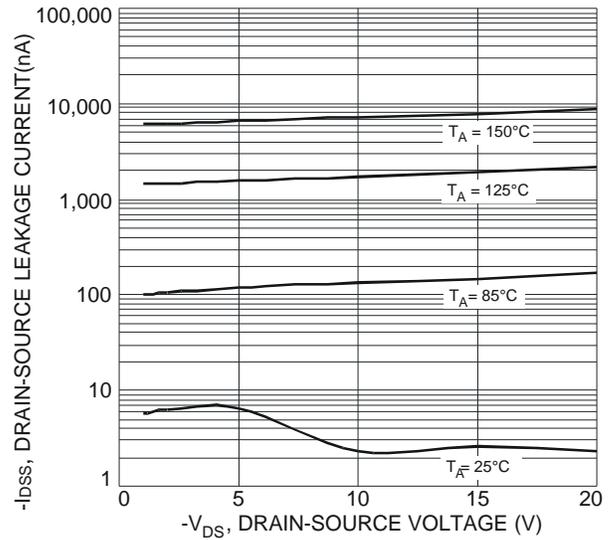


Fig. 21 Typical Drain-Source Leakage Current vs. Drain-Source Voltage

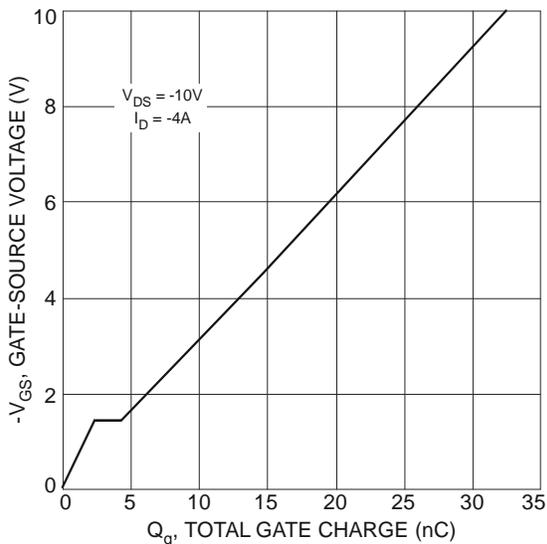
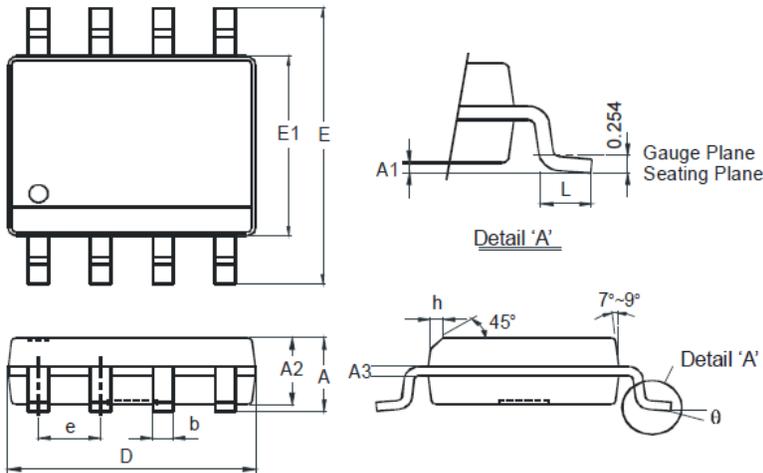


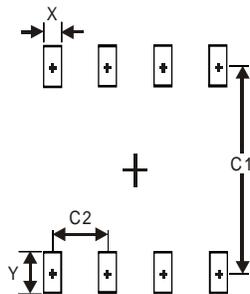
Fig. 22 Gate-Source Voltage vs. Total Gate Charge

### Package Outline Dimensions



SO-8		
Dim	Min	Max
A	-	1.75
A1	0.10	0.20
A2	1.30	1.50
A3	0.15	0.25
b	0.3	0.5
D	4.85	4.95
E	5.90	6.10
E1	3.85	3.95
e	1.27 Typ	
h	-	0.35
L	0.62	0.82
θ	0°	8°
All Dimensions in mm		

### Suggested Pad Layout



Dimensions	Value (in mm)
X	0.60
Y	1.55
C1	5.4
C2	1.27